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Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Active
Number of LABs/CLBs	1000
Number of Logic Elements/Cells	8000
Total RAM Bits	226304
Number of I/O	86
Number of Gates	-
Voltage - Supply	1.14V ~ 1.26V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	132-LFBGA, CSPBGA
Supplier Device Package	132-CSBGA (8x8)
Purchase URL	https://www.e-xfl.com/product-detail/lattice-semiconductor/lfxp2-8e-6mn132i

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Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong



Figure 2-3. Slice Diagram



DI[3:2] for Slice 2 and DI[1:0] for Slice 0 data

WAD [A:D] is a 4bit address from slice 1 LUT input

Table 2-2. Slice Signal Descriptions

Function	Туре	Signal Names	Description
Input	Data signal	A0, B0, C0, D0	Inputs to LUT4
Input	Data signal	A1, B1, C1, D1	Inputs to LUT4
Input	Multi-purpose	MO	Multipurpose Input
Input	Multi-purpose	M1	Multipurpose Input
Input	Control signal	CE	Clock Enable
Input	Control signal	LSR	Local Set/Reset
Input	Control signal	CLK	System Clock
Input	Inter-PFU signal	FCI	Fast Carry-In ¹
Input	Inter-slice signal	FXA	Intermediate signal to generate LUT6 and LUT7
Input	Inter-slice signal	FXB	Intermediate signal to generate LUT6 and LUT7
Output	Data signals	F0, F1	LUT4 output register bypass signals
Output	Data signals	Q0, Q1	Register outputs
Output	Data signals	OFX0	Output of a LUT5 MUX
Output	Data signals	OFX1	Output of a LUT6, LUT7, LUT8 ² MUX depending on the slice
Output	Inter-PFU signal	FCO	Slice 2 of each PFU is the fast carry chain output ¹

1. See Figure 2-3 for connection details.

2. Requires two PFUs.



Edge Clock Sources

Edge clock resources can be driven from a variety of sources at the same edge. Edge clock resources can be driven from adjacent edge clock PIOs, primary clock PIOs, PLLs and clock dividers as shown in Figure 2-8.

Figure 2-8. Edge Clock Sources



Note: This diagram shows sources for the XP2-17 device. Smaller LatticeXP2 devices have two GPLLs.



Figure 2-12. Secondary Clock Selection



Slice Clock Selection

Figure 2-13 shows the clock selections and Figure 2-14 shows the control selections for Slice0 through Slice2. All the primary clocks and the four secondary clocks are routed to this clock selection mux. Other signals, via routing, can be used as clock inputs to the slices. Slice controls are generated from the secondary clocks or other signals connected via routing.

If none of the signals are selected for both clock and control, then the default value of the mux output is 1. Slice 3 does not have any registers; therefore it does not have the clock or control muxes.

Figure 2-13. Slice0 through Slice2 Clock Selection





Figure 2-14. Slice0 through Slice2 Control Selection



Edge Clock Routing

LatticeXP2 devices have eight high-speed edge clocks that are intended for use with the PIOs in the implementation of high-speed interfaces. Each device has two edge clocks per edge. Figure 2-15 shows the selection muxes for these clocks.

Figure 2-15. Edge Clock Mux Connections





sysMEM Memory

LatticeXP2 devices contains a number of sysMEM Embedded Block RAM (EBR). The EBR consists of 18 Kbit RAM with dedicated input and output registers.

sysMEM Memory Block

The sysMEM block can implement single port, dual port or pseudo dual port memories. Each block can be used in a variety of depths and widths as shown in Table 2-5. FIFOs can be implemented in sysMEM EBR blocks by using support logic with PFUs. The EBR block supports an optional parity bit for each data byte to facilitate parity checking. EBR blocks provide byte-enable support for configurations with18-bit and 36-bit data widths.

Table 2-5. sysMEM Block Configurations

Memory Mode	Configurations
Single Port	16,384 x 1 8,192 x 2 4,096 x 4 2,048 x 9 1,024 x 18 512 x 36
True Dual Port	16,384 x 1 8,192 x 2 4,096 x 4 2,048 x 9 1,024 x 18
Pseudo Dual Port	16,384 x 1 8,192 x 2 4,096 x 4 2,048 x 9 1,024 x 18 512 x 36

Bus Size Matching

All of the multi-port memory modes support different widths on each of the ports. The RAM bits are mapped LSB word 0 to MSB word 0, LSB word 1 to MSB word 1, and so on. Although the word size and number of words for each port varies, this mapping scheme applies to each port.

FlashBAK EBR Content Storage

All the EBR memory in the LatticeXP2 is shadowed by Flash memory. Optionally, initialization values for the memory blocks can be defined using the Lattice Diamond design tools. The initialization values are loaded into the Flash memory during device programming and into the SRAM at power up or whenever the device is reconfigured. This feature is ideal for the storage of a variety of information such as look-up tables and microprocessor code. It is also possible to write the current contents of the EBR memory back to Flash memory. This capability is useful for the storage of data such as error codes and calibration information. For additional information on the FlashBAK capability see TN1137, LatticeXP2 Memory Usage Guide.







sysDSP Block Capabilities

The sysDSP block in the LatticeXP2 family supports four functional elements in three 9, 18 and 36 data path widths. The user selects a function element for a DSP block and then selects the width and type (signed/unsigned) of its operands. The operands in the LatticeXP2 family sysDSP Blocks can be either signed or unsigned but not mixed within a function element. Similarly, the operand widths cannot be mixed within a block. DSP elements can be concatenated.

The resources in each sysDSP block can be configured to support the following four elements:

- MULT (Multiply)
- MAC (Multiply, Accumulate)
- MULTADDSUB (Multiply, Addition/Subtraction)
- MULTADDSUBSUM (Multiply, Addition/Subtraction, Accumulate)

The number of elements available in each block depends on the width selected from the three available options: x9, x18, and x36. A number of these elements are concatenated for highly parallel implementations of DSP functions. Table 2-6 shows the capabilities of the block.

Width of Multiply	x9	x18	x36
MULT	8	4	1
MAC	2	2	_
MULTADDSUB	4	2	_
MULTADDSUBSUM	2	1	_

Some options are available in four elements. The input register in all the elements can be directly loaded or can be loaded as shift register from previous operand registers. By selecting 'dynamic operation' the following operations are possible:



Programmable I/O Cells (PIC)

Each PIC contains two PIOs connected to their respective sysIO buffers as shown in Figure 2-25. The PIO Block supplies the output data (DO) and the tri-state control signal (TO) to the sysIO buffer and receives input from the buffer. Table 2-11 provides the PIO signal list.

Figure 2-25. PIC Diagram



Signals are available on left/right/bottom edges only.
 Selected blocks.

Two adjacent PIOs can be joined to provide a differential I/O pair (labeled as "T" and "C") as shown in Figure 2-25. The PAD Labels "T" and "C" distinguish the two PIOs. Approximately 50% of the PIO pairs on the left and right edges of the device can be configured as true LVDS outputs. All I/O pairs can operate as inputs.



shows the diagram using this gearbox function. For more information on this topic, see TN1138, <u>LatticeXP2 High</u> <u>Speed I/O Interface</u>.







Figure 2-31. DQS Local Bus



*DQSXFERDEL shifts ECLK1 by 90% and is not associated with a particular PIO.

Polarity Control Logic

In a typical DDR memory interface design, the phase relationship between the incoming delayed DQS strobe and the internal system clock (during the READ cycle) is unknown. The LatticeXP2 family contains dedicated circuits to transfer data between these domains. To prevent set-up and hold violations, at the domain transfer between DQS (delayed) and the system clock, a clock polarity selector is used. This changes the edge on which the data is registered in the synchronizing registers in the input register block and requires evaluation at the start of each READ cycle for the correct clock polarity.

Prior to the READ operation in DDR memories, DQS is in tristate (pulled by termination). The DDR memory device drives DQS low at the start of the preamble state. A dedicated circuit detects this transition. This signal is used to control the polarity of the clock to the synchronizing registers.



LatticeXP2 Family Data Sheet DC and Switching Characteristics

September 2014

Data Sheet DS1009

Absolute Maximum Ratings^{1, 2, 3}

Supply Voltage V _{CC}
Supply Voltage V _{CCAUX}
Supply Voltage V _{CCJ}
Supply Voltage V _{CCPLL} ⁴ 0.5 to 3.75V
Output Supply Voltage V _{CCIO} 0.5 to 3.75V
Input or I/O Tristate Voltage Applied ⁵ 0.5 to 3.75V
Storage Temperature (Ambient)65 to 150°C
Junction Temperature Under Bias (Tj)+125°C

1. Stress above those listed under the "Absolute Maximum Ratings" may cause permanent damage to the device. Functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

2. Compliance with the Lattice <u>Thermal Management</u> document is required.

3. All voltages referenced to GND.

4. V_{CCPLL} only available on csBGA, PQFP and TQFP packages.

5. Overshoot and undershoot of -2V to (V_{IHMAX} + 2) volts is permitted for a duration of <20 ns.

Recommended Operating Conditions

Symbol	Parameter	Min.	Max.	Units
V _{CC}	Core Supply Voltage	1.14	1.26	V
V _{CCAUX} ^{4, 5}	Auxiliary Supply Voltage	3.135	3.465	V
V _{CCPLL} ¹	PLL Supply Voltage	3.135	3.465	V
V _{CCIO} ^{2, 3, 4}	I/O Driver Supply Voltage	1.14	3.465	V
V _{CCJ} ²	Supply Voltage for IEEE 1149.1 Test Access Port	1.14	3.465	V
t _{JCOM}	Junction Temperature, Commercial Operation	0	85	°C
t _{JIND}	Junction Temperature, Industrial Operation	-40	100	°C

1. V_{CCPLL} only available on csBGA, PQFP and TQFP packages.

If V_{CCIO} or V_{CCJ} is set to 1.2 V, they must be connected to the same power supply as V_{CC}. If V_{CCIO} or V_{CCJ} is set to 3.3V, they must be connected to the same power supply as V_{CCAUX}.

3. See recommended voltages by I/O standard in subsequent table.

4. To ensure proper I/O behavior, V_{CCIO} must be turned off at the same time or earlier than V_{CCAUX} .

5. In fpBGA and ftBGA packages, the PLLs are connected to, and powered from, the auxiliary power supply.

On-Chip Flash Memory Specifications

Symbol	Parameter	Max.	Units	
Nanagaya	Flash Programming Cycles per t _{RETENTION} ¹	10,000	Cycles	
NPROGCYC	Flash Functional Programming Cycles	100,000	Cycles	

1. The minimum data retention, t_{RETENTION}, is 20 years.

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Supply Current (Standby)^{1, 2, 3, 4}

Symbol	Parameter	Device	Typical⁵	Units
I _{CC}		XP2-5	14	mA
		XP2-8	18	mA
	Core Power Supply Current	XP2-17	24	mA
		XP2-30	35	mA
		XP2-40 45 mA XP2-5 15 mA XP2-8 15 mA	mA	
		XP2-5	15	mA
	Auxiliary Power Supply Current ⁶	XP2-8	15	mA
I _{CCAUX}		XP2-17	15	mA
		XP2-30	16	mA
		XP2-40	16	mA
I _{CCPLL}	PLL Power Supply Current (per PLL)		0.1	mA
I _{CCIO}	Bank Power Supply Current (per bank)		2	mA
I _{CCJ}	V _{CCJ} Power Supply Current		0.25	mA

Over Recommended Operating Conditions

1. For further information on supply current, please see TN1139, Power Estimation and Management for LatticeXP2 Devices.

2. Assumes all outputs are tristated, all inputs are configured as LVCMOS and held at the V_{CCIO} or GND.

3. Frequency 0 MHz.

4. Pattern represents a "blank" configuration data file.

5. $T_J = 25^{\circ}C$, power supplies at nominal voltage.

6. In fpBGA and ftBGA packages the PLLs are connected to and powered from the auxiliary power supply. For these packages, the actual auxiliary supply current is the sum of I_{CCAUX} and I_{CCPLL}. For csBGA, PQFP and TQFP packages the PLLs are powered independent of the auxiliary power supply.



Table 3-1. LVDS25E DC Conditions

Parameter	Description	Typical	Units
V _{CCIO}	Output Driver Supply (+/-5%)	2.50	V
Z _{OUT}	Driver Impedance	20	Ω
R _S	Driver Series Resistor (+/-1%)	158	Ω
R _P	Driver Parallel Resistor (+/-1%)	140	Ω
R _T	Receiver Termination (+/-1%)	100	Ω
V _{OH}	Output High Voltage (after R _P)	1.43	V
V _{OL}	Output Low Voltage (after R _P)	1.07	V
V _{OD}	Output Differential Voltage (After R _P)	0.35	V
V _{CM}	Output Common Mode Voltage	1.25	V
Z _{BACK}	Back Impedance	100.5	Ω
I _{DC}	DC Output Current	6.03	mA

LVCMOS33D

All I/O banks support emulated differential I/O using the LVCMOS33D I/O type. This option, along with the external resistor network, provides the system designer the flexibility to place differential outputs on an I/O bank with 3.3V VCCIO. The default drive current for LVCMOS33D output is 12mA with the option to change the device strength to 4mA, 8mA, 16mA or 20mA. Follow the LVCMOS33 specifications for the DC characteristics of the LVCMOS33D.



BLVDS

The LatticeXP2 devices support the BLVDS standard. This standard is emulated using complementary LVCMOS outputs in conjunction with a parallel external resistor across the driver outputs. BLVDS is intended for use when multi-drop and bi-directional multi-point differential signaling is required. The scheme shown in Figure 3-2 is one possible solution for bi-directional multi-point differential signals.





Table 3-2. BLVDS DC Conditions¹

		Тур		
Parameter	Description	Ζο = 45 Ω	Ζο = 90 Ω	Units
V _{CCIO}	Output Driver Supply (+/- 5%)	2.50	2.50	V
Z _{OUT}	Driver Impedance	10.00	10.00	Ω
R _S	Driver Series Resistor (+/- 1%)	90.00	90.00	Ω
R _{TL}	Driver Parallel Resistor (+/- 1%)	45.00	90.00	Ω
R _{TR}	Receiver Termination (+/- 1%)	45.00	90.00	Ω
V _{OH}	Output High Voltage (After R _{TL})	1.38	1.48	V
V _{OL}	Output Low Voltage (After R _{TL})	1.12	1.02	V
V _{OD}	Output Differential Voltage (After R _{TL})	0.25	0.46	V
V _{CM}	Output Common Mode Voltage	1.25	1.25	V
I _{DC}	DC Output Current	11.24	10.20	mA

Over Recommended Operating Conditions

1. For input buffer, see LVDS table.



LatticeXP2 External Switching Characteristics (Continued)

			-	7	-6		-5		
Parameter	Description	Device	Min.	Max.	Min.	Max.	Min.	Max.	Units
		XP2-5	1.00		1.30	_	1.60		ns
		XP2-8	1.00	_	1.30	_	1.60	_	ns
t _{HE}	Clock to Data Hold - PIO Input Register	XP2-17	1.00		1.30	_	1.60		ns
		XP2-30	1.20		1.60	_	1.90		ns
		XP2-40	1.20		1.60		1.90		ns
		XP2-5	1.00		1.30	_	1.60		ns
		XP2-8	1.00		1.30	_	1.60		ns
t _{SU_DELE}	Clock to Data Setup - PIO Input Begister with Data Input Delay	XP2-17	1.00		1.30	_	1.60		ns
		XP2-30	1.20		1.60		1.90		ns
		XP2-40	1.20		1.60		1.90		ns
		XP2-5	0.00		0.00		0.00		ns
		XP2-8	0.00	—	0.00	—	0.00	—	ns
t _{H_DELE}	Clock to Data Hold - PIO Input Begister with Input Data Delay	XP2-17	0.00	—	0.00	—	0.00	—	ns
		XP2-30	0.00		0.00		0.00		ns
		XP2-40	0.00		0.00		0.00		ns
f _{MAX_IOE}	Clock Frequency of I/O and PFU Register	XP2	_	420	_	357	_	311	MHz
General I/O Pir	Parameters (using Primary Clo	ck with PLL)1	1	1	1	1	1	
		XP2-5	—	3.00	—	3.30	—	3.70	ns
		XP2-8		3.00		3.30		3.70	ns
t _{COPLL}	Clock to Output - PIO Output	XP2-17		3.00		3.30		3.70	ns
		XP2-30	_	3.00		3.30		3.70	ns
		XP2-40		3.00		3.30		3.70	ns
		XP2-5	1.00		1.20		1.40		ns
		XP2-8	1.00		1.20		1.40		ns
t _{SUPLL}	Clock to Data Setup - PIO Input Register	XP2-17	1.00		1.20		1.40		ns
		XP2-30	1.00		1.20		1.40		ns
		XP2-40	1.00		1.20	_	1.40		ns
		XP2-5	0.90		1.10		1.30		ns
		XP2-8	0.90		1.10		1.30		ns
t _{HPLL}	Clock to Data Hold - PIO Input	XP2-17	0.90		1.10		1.30		ns
		XP2-30	1.00	—	1.20	—	1.40	—	ns
		XP2-40	1.00	—	1.20	—	1.40	—	ns
		XP2-5	1.90	—	2.10	—	2.30	—	ns
		XP2-8	1.90		2.10	—	2.30	_	ns
t _{SU_DELPLL}	Clock to Data Setup - PIO Input Begister with Data Input Delay	XP2-17	1.90	—	2.10	—	2.30	—	ns
	lingibion with Data input Delay	XP2-30	2.00	—	2.20	—	2.40	—	ns
		XP2-40	2.00	—	2.20	—	2.40	—	ns

Over Recommended Operating Conditions



On-Chip Oscillator and Configuration Master Clock Characteristics

Parameter	Min.	Max.	Units
Master Clock Frequency	Selected value -30%	Selected value +30%	MHz
Duty Cycle	40	60	%

Over Recommended Operating Conditions

Figure 3-9. Master SPI Configuration Waveforms





Signal Descriptions (Cont.)

Signal Name	I/O	Description
TDO	0	Output pin. Test Data Out pin used to shift data out of a device using 1149.1.
VCCJ		Power supply pin for JTAG Test Access Port.
Configuration Pads (Used during sysC	ONFIG)	
CFG[1:0]	Ι	Mode pins used to specify configuration mode values latched on rising edge of INITN. During configuration, an internal pull-up is enabled.
INITN ¹	I/O	Open Drain pin. Indicates the FPGA is ready to be configured. During configuration, a pull-up is enabled.
PROGRAMN	I	Initiates configuration sequence when asserted low. This pin always has an active pull-up.
DONE	I/O	Open Drain pin. Indicates that the configuration sequence is complete, and the startup sequence is in progress.
CCLK	I/O	Configuration Clock for configuring an FPGA in sysCONFIG mode.
SISPI ²	I/O	Input data pin in slave SPI mode and Output data pin in Master SPI mode.
SOSPI ²	I/O	Output data pin in slave SPI mode and Input data pin in Master SPI mode.
CSSPIN ²	0	Chip select for external SPI Flash memory in Master SPI mode. This pin has a weak internal pull-up.
CSSPISN	I	Chip select in Slave SPI mode. This pin has a weak internal pull-up.
TOE	I	Test Output Enable tristates all I/O pins when driven low. This pin has a weak internal pull-up, but when not used an external pull-up to $V_{\rm CC}$ is recommended.

1. If not actively driven, the internal pull-up may not be sufficient. An external pull-up resistor of 4.7k to $10k\Omega$ is recommended.

2. When using the device in Master SPI mode, it must be mutually exclusive from JTAG operations (i.e. TCK tied to GND) or the JTAG TCK must be free-running when used in a system JTAG test environment. If Master SPI mode is used in conjunction with a JTAG download cable, the device power cycle is required after the cable is unplugged.



Pin Information Summary

	XP2-5 XP2-8			XP2-17			XP2-30		XP2-40								
Pin Ty	ре	132 csBGA	144 TQFP	208 PQFP	256 ftBGA	132 csBGA	144 TQFP	208 PQFP	256 ftBGA	208 PQFP	256 ftBGA	484 fpBGA	256 ftBGA	484 fpBGA	672 fpBGA	484 fpBGA	672 fpBGA
Single Ended Use	er I/O	86	100	146	172	86	100	146	201	146	201	358	201	363	472	363	540
Differential Pair	Normal	35	39	57	66	35	39	57	77	57	77	135	77	137	180	137	204
User I/O	Highspeed	8	11	16	20	8	11	16	23	16	23	44	23	44	56	44	66
	TAP	5	5	5	5	5	5	5	5	5	5	5	5	5	5	5	5
Configuration	Muxed	9	9	9	9	9	9	9	9	9	9	9	9	9	9	9	9
	Dedicated	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1
Non Configura-	Muxed	5	5	7	7	7	7	9	9	11	11	21	7	11	13	11	13
tion	Dedicated	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1	1
Vcc		6	4	9	6	6	4	9	6	9	6	16	6	16	20	16	20
Vccaux		4	4	4	4	4	4	4	4	4	4	8	4	8	8	8	8
VCCPLL		2	2	2	-	2	2	2	-	4	-	-	-	-	-	-	-
	Bank0	2	2	2	2	2	2	2	2	2	2	4	2	4	4	4	4
	Bank1	1	1	2	2	1	1	2	2	2	2	4	2	4	4	4	4
	Bank2	2	2	2	2	2	2	2	2	2	2	4	2	4	4	4	4
VCCIO	Bank3	1	1	2	2	1	1	2	2	2	2	4	2	4	4	4	4
10010	Bank4	1	1	2	2	1	1	2	2	2	2	4	2	4	4	4	4
	Bank5	2	2	2	2	2	2	2	2	2	2	4	2	4	4	4	4
	Bank6	1	1	2	2	1	1	2	2	2	2	4	2	4	4	4	4
	Bank7	2	2	2	2	2	2	2	2	2	2	4	2	4	4	4	4
GND, GND0-GNI	77	15	15	20	20	15	15	22	20	22	20	56	20	56	64	56	64
NC		-	-	4	31	-	-	2	2	-	2	7	2	2	69	2	1
	Bank0	18/9	20/10	20/10	26/13	18/9	20/10	20/10	28/14	20/10	28/14	52/26	28/14	52/26	70/35	52/26	70/35
	Bank1	4/2	6/3	18/9	18/9	4/2	6/3	18/9	22/11	18/9	22/11	36/18	22/11	36/18	54/27	36/18	70/35
	Bank2	16/8	18/9	18/9	22/11	16/8	18/9	18/9	26/13	18/9	26/13	46/23	26/13	46/23	56/28	46/23	64/32
Single Ended/	Bank3	4/2	4/2	16/8	20/10	4/2	4/2	16/8	24/12	16/8	24/12	44/22	24/12	46/23	56/28	46/23	66/33
per Bank	Bank4	8/4	8/4	18/9	18/9	8/4	8/4	18/9	26/13	18/9	26/13	36/18	26/13	38/19	54/27	38/19	70/35
	Bank5	14/7	18/9	20/10	24/12	14/7	18/9	20/10	24/12	20/10	24/12	52/26	24/12	53/26	70/35	53/26	70/35
	Bank6	6/3	8/4	18/9	22/11	6/3	8/4	18/9	27/13	18/9	27/13	46/23	27/13	46/23	56/28	46/23	66/33
	Bank7	16/8	18/9	18/9	22/11	16/8	18/9	18/9	24/12	18/9	24/12	46/23	24/12	46/23	56/28	46/23	64/32
	Bank0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
	Bank1	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
	Bank2	3	4	4	5	3	4	4	6	4	6	11	6	11	14	11	16
True LVDS Pairs	Bank3	1	1	4	5	1	1	4	6	4	6	11	6	11	14	11	17
Bank	Bank4	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
	Bank5	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0	0
	Bank6	1	2	4	5	1	2	4	6	4	6	11	6	11	14	11	17
	Bank7	3	4	4	5	3	4	4	5	4	5	11	5	11	14	11	16
	Bank0	1	1	1	1	1	1	1	1	1	1	3	1	2	4	2	4
	Bank1	0	0	1	1	0	0	1	1	1	1	2	1	2	3	2	4
	Bank2	1	1	1	1	1	1	1	1	1	1	2	1	3	3	3	4
DDR Banks	Bank3	0	0	1	1	0	0	1	1	1	1	2	1	3	3	3	4
I/O Bank ¹	Bank4	0	0	1	1	0	0	1	1	1	1	2	1	2	3	2	4
	Bank5	1	1	1	1	1	1	1	1	1	1	3	1	2	4	2	4
	Bank6	0	0	1	1	0	0	1	1	1	1	2	1	3	3	3	4
	Bank7	1	1	1	1	1	1	1	1	1	1	2	1	3	3	3	4



Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-30E-5FTN256C	1.2V	-5	Lead-Free ftBGA	256	COM	30
LFXP2-30E-6FTN256C	1.2V	-6	Lead-Free ftBGA	256	COM	30
LFXP2-30E-7FTN256C	1.2V	-7	Lead-Free ftBGA	256	COM	30
LFXP2-30E-5FN484C	1.2V	-5	Lead-Free fpBGA	484	COM	30
LFXP2-30E-6FN484C	1.2V	-6	Lead-Free fpBGA	484	COM	30
LFXP2-30E-7FN484C	1.2V	-7	Lead-Free fpBGA	484	COM	30
LFXP2-30E-5FN672C	1.2V	-5	Lead-Free fpBGA	672	COM	30
LFXP2-30E-6FN672C	1.2V	-6	Lead-Free fpBGA	672	COM	30
LFXP2-30E-7FN672C	1.2V	-7	Lead-Free fpBGA	672	COM	30

Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-40E-5FN484C	1.2V	-5	Lead-Free fpBGA	484	COM	40
LFXP2-40E-6FN484C	1.2V	-6	Lead-Free fpBGA	484	COM	40
LFXP2-40E-7FN484C	1.2V	-7	Lead-Free fpBGA	484	COM	40
LFXP2-40E-5FN672C	1.2V	-5	Lead-Free fpBGA	672	COM	40
LFXP2-40E-6FN672C	1.2V	-6	Lead-Free fpBGA	672	COM	40
LFXP2-40E-7FN672C	1.2V	-7	Lead-Free fpBGA	672	COM	40

Industrial

Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-5E-5MN132I	1.2V	-5	Lead-Free csBGA	132	IND	5
LFXP2-5E-6MN132I	1.2V	-6	Lead-Free csBGA	132	IND	5
LFXP2-5E-5TN144I	1.2V	-5	Lead-Free TQFP	144	IND	5
LFXP2-5E-6TN144I	1.2V	-6	Lead-Free TQFP	144	IND	5
LFXP2-5E-5QN208I	1.2V	-5	Lead-Free PQFP	208	IND	5
LFXP2-5E-6QN208I	1.2V	-6	Lead-Free PQFP	208	IND	5
LFXP2-5E-5FTN256I	1.2V	-5	Lead-Free ftBGA	256	IND	5
LFXP2-5E-6FTN256I	1.2V	-6	Lead-Free ftBGA	256	IND	5

Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-8E-5MN132I	1.2V	-5	Lead-Free csBGA	132	IND	8
LFXP2-8E-6MN132I	1.2V	-6	Lead-Free csBGA	132	IND	8
LFXP2-8E-5TN144I	1.2V	-5	Lead-Free TQFP	144	IND	8
LFXP2-8E-6TN144I	1.2V	-6	Lead-Free TQFP	144	IND	8
LFXP2-8E-5QN208I	1.2V	-5	Lead-Free PQFP	208	IND	8
LFXP2-8E-6QN208I	1.2V	-6	Lead-Free PQFP	208	IND	8
LFXP2-8E-5FTN256I	1.2V	-5	Lead-Free ftBGA	256	IND	8
LFXP2-8E-6FTN256I	1.2V	-6	Lead-Free ftBGA	256	IND	8



Part Number	Voltage	Grade	Package	Pins	Temp.	LUTs (k)
LFXP2-40E-5F484I	1.2V	-5	fpBGA	484	IND	40
LFXP2-40E-6F484I	1.2V	-6	fpBGA	484	IND	40
LFXP2-40E-5F672I	1.2V	-5	fpBGA	672	IND	40
LFXP2-40E-6F672I	1.2V	-6	fpBGA	672	IND	40



Date	Version	Section	Change Summary
April 2008	01.4	DC and Switching	Updated Flash Download Time (From On-Chip Flash to SRAM) Table
(cont.)	(cont.)	Characteristics (cont.)	Updated Flash Program Time Table
			Updated Flash Erase Time Table
			Updated FlashBAK (from EBR to Flash) Table
			Updated Hot Socketing Specifications Table footnotes
		Pinout Information	Updated Signal Descriptions Table
June 2008	01.5	Architecture	Removed Read-Before-Write sysMEM EBR mode.
			Clarification of the operation of the secondary clock regions.
		DC and Switching Characteristics	Removed Read-Before-Write sysMEM EBR mode.
		Pinout Information	Updated DDR Banks Bonding Out per I/O Bank section of Pin Informa- tion Summary Table.
August 2008	01.6	—	Data sheet status changed from preliminary to final.
		Architecture	Clarification of the operation of the secondary clock regions.
		DC and Switching Characteristics	Removed "8W" specification from Hot Socketing Specifications table.
			Removed "8W" footnote from DC Electrical Characteristics table.
			Updated Register-to-Register Performance table.
		Ordering Information	Removed "8W" option from Part Number Description.
			Removed XP2-17 "8W" OPNs.
April 2011	01.7	DC and Switching Characteristics	Recommended Operating Conditions table, added footnote 5.
			On-Chip Flash Memory Specifications table, added footnote 1.
			BLVDS DC Conditions, corrected column title to be Z0 = 90 ohms.
			sysCONFIG Port Timing Specifications table, added footnote 1 for t _{DINIT} .
January 2012	01.8	Multiple	Added support for Lattice Diamond design software.
		Architecture	Corrected information regarding SED support.
		DC and Switching Characteristics	Added reference to ESD Performance Qualification Summary informa- tion.
May 2013	01.9	All	Updated document with new corporate logo.
		Architecture	Architecture Overview – Added information on the state of the register on power up and after configuration.
			Added information regarding SED support.
		DC and Switching Characteristics	Removed Input Clock Rise/Fall Time 1ns max from the sysCLOCK PLL Timing table.
		Ordering Information	Updated topside mark in Ordering Information diagram.
March 2014	02.0	Architecture	Updated Typical sysIO I/O Behavior During Power-up section. Added information on POR signal deactivation.
August 2014	02.1	Architecture	Updated Typical sysIO I/O Behavior During Power-up section. Described user I/Os during power up and before FPGA core logic is active.
September 2014	2.2	DC and Switching Characteristics	Updated Switching Test Conditions section. Re-linked missing figure.